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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with **MPEP 609**; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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1011/	A01 A02	US 6,224,332	May 1, 2001	Leach et al.			415	126		
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/DH/	A04	JP 2002-160132	Jun. 4, 2002	JP-Japan			See English Abstract			
<u>/DH/</u>	A05	JP 2003-071654	Mar. 12, 2003	JP-Japan	_		See English Abstract			-
/DH/	A06	JP 01-254477	Oct. 11, 1989	JP-Japan			See English Abstract			_
/DH/	A07	JP 2000-111450	Apr. 21, 2000	JP-Japan			See English Abstract			
/DH/	A08	JP 07-133859	May 23, 1995	JP-Japan			See English Abstract			
/DH/	A09	JP 11-011613	Jan. 19, 1999	JP-Japan			See English Abstract			_
/DH/	A10	JP 05-063989	Sep. 27, 1994	JP-Japan			See English Abstract			
/DH/	A11	JP 2000-356108	Dec. 26, 2000	JP-Japan			In English and also see US 6,224,332			
	A12									
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		OTHER REFE	RENCES (Incl	uding Author, Title	e, Date, F	Pertinen	t Pages,	Etc.)		
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/Douglas Hess/